

## Recent Advances in Signature Biometrics

Dr. Julian Fierrez

Biometric Recognition Group – ATVS  
Escuela Politécnica Superior  
Universidad Autónoma de Madrid, Spain

(Visiting scholar at)  
Pattern Recognition and Image Proc. Lab.  
Dept. of Computer Science & Engineering  
Michigan State University



August, 2008 - PRIP Seminar - Dept. Computer Science and Engineering, Michigan State University

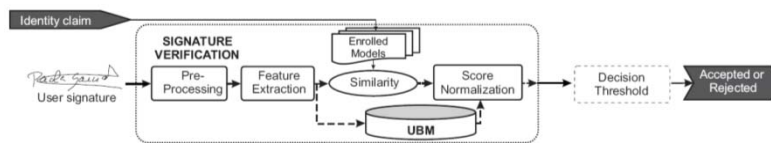
## Recent Advances in Signature Biometrics

- Universal Background Models
- User-dependent HMMs
- Device-dependent Feature Selection

## Recent advances in online signature: UBMs (I)

### • Universal Background Models (UBMs):

- Statistical Models of an “average” user
- During enrollment, the user model is adapted from the UBM using the training data (robust against small training set sizes)
- In the matching process, the user signature is compared to his claimed template and the resulting score is normalized by its similarity to the UBM
- UBMs have been applied with great success in Speaker Verification Systems



- Results (tablet): approx. half EER\_random while maintaining EER\_skilled

[Martinez-Diaz, Fierrez, et al., IEEE BTAS 2007]

Julian Fierrez, PRIP Seminar, Dept. CSE, MSU – August 13, 2008

3

## Recent advances in online signature: UBMs (II)

- Adaptation is based on the Maximum a Posteriori (MAP) algorithm.
- For each user, a specific set of GMM parameters is derived:

Probabilistic alignment and sufficient statistics between the user vector  $\mathbf{x}_i$  and the UBM are computed

$$P(i | \mathbf{x}_i) = \frac{\omega_i p_i(\mathbf{x}_i)}{\sum_{j=1}^N \omega_j p_j(\mathbf{x}_i)}$$

$$n_i = \sum_{t=1}^T \omega_i P(i | \mathbf{x}_t)$$

$$E_i(\mathbf{x}) = \frac{1}{n_i} \sum_{t=1}^T P(i | \mathbf{x}_t) \mathbf{x}_t$$

$$E_i(\mathbf{x}^2) = \frac{1}{n_i} \sum_{t=1}^T P(i | \mathbf{x}_t) \mathbf{x}_t^2$$

The adaptation coefficient  $\alpha$  controls the contribution of old and new parameters

$$\alpha = \frac{n_i}{n_i + r}$$

Relevance factor (must be specified)

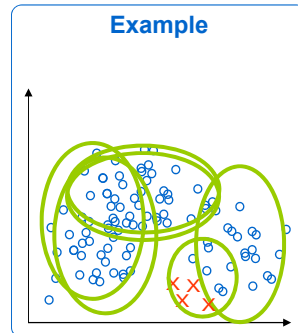
Parameters are updated

$$\hat{\omega}_i = [\alpha n_i / T + (1 - \alpha) \omega_i] \gamma$$

$$\hat{\mu}_i = \alpha E_i(\mathbf{x}) + (1 - \alpha) \mu_i$$

$$\hat{\sigma}_i^2 = \alpha E_i(\mathbf{x}^2) + (1 - \alpha) (\sigma_i^2 - \mu_i^2) - \hat{\mu}_i^2$$

Example



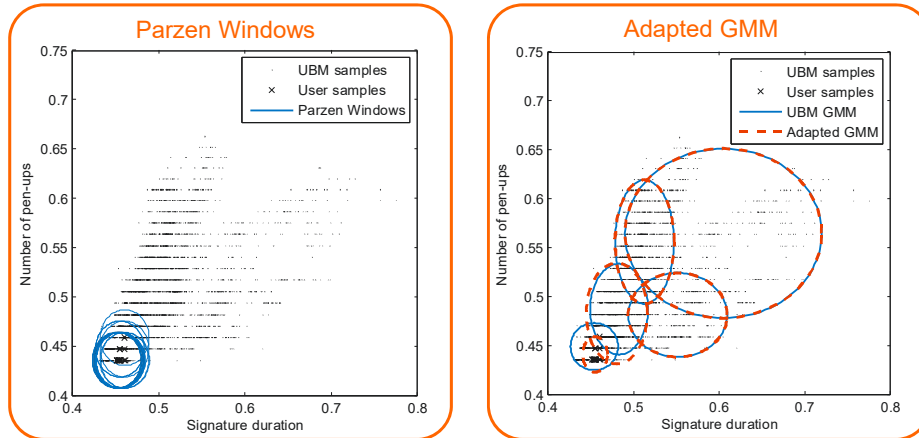
[Martinez-Diaz, Fierrez, et al., IEEE BTAS 2007]

Julian Fierrez, PRIP Seminar, Dept. CSE, MSU – August 13, 2008

4

## Recent advances in online signature: UBMs (III)

- Example of 2-dimensional Parzen Windows and Adapted GMM:



[Martinez-Diaz, Fierrez, et al., IEEE BTAS 2007]

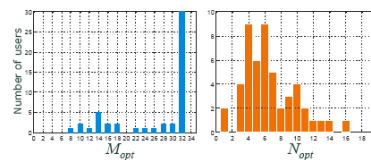
Julian Fierrez, PRIP Seminar, Dept. CSE, MSU – August 13, 2008

5

## Recent advances in online signature: UD HMMs



Histograms of  $N_{opt}$  and  $M_{opt}$  for  $D=42$  and  $M_{max}=32$



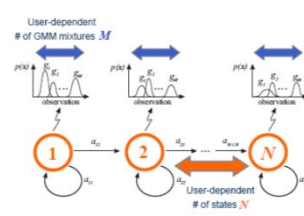
**Number of Gaussian Mixtures**

$$M_{opt} = \arg \max_{M \in M_{max}} \frac{\sum_{i=1}^K \text{like}(S_i, \lambda) / T_i}{K}$$

**Number of States**

$$N_{opt} = \frac{\sum_{i=1}^K T_i}{K \cdot D}$$

$T_i$ : signature length  
 $K$ : # training signatures  
 $D$ : division factor

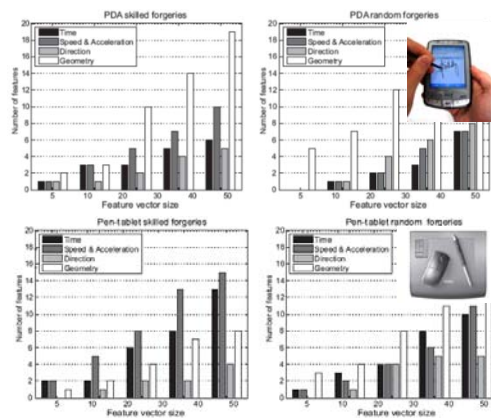


Scenario	EER random forgeries	EER skilled forgeries
Baseline ( $N=4$ ; $M=10$ )	7.3%	20.5%
User-dependent ( $D=42$ ; $M_{max}=32$ )	5.2%	15.8%

[Martinez-Diaz, Fierrez, et al., ICFHR 2007]

Julian Fierrez, PRIP Seminar, Dept. CSE, MSU – August 13, 2008

6



- The best set of features is very different between Tablet and PDA, specially for skilled forgeries:
  - Features based on Time, Speed, and Acceleration are best for Tablet
  - Geometry features are best for PDA



**Table 1. PDA scenario EER comparison for random (rd) and skilled (sk) forgeries.**

System	$EER_{rd}$	$EER_{sk}$
Proposed system (HMM+features)	4.0%	11.9%
BMEC best for skilled forgeries [11]	8.07%	13.43%
BMEC best for random forgeries [8]	4.03%	13.58%

- Future work: Biosecure Signature Evaluation Campaign (ICB-09)

[Martinez-Diaz, Fierrez, et al., ICPR 2007]

Julian Fierrez, PRIP Seminar, Dept. CSE, MSU – August 13, 2008

7

## Recent Advances in Signature Biometrics

Dr. Julian Fierrez

(Visiting scholar at)

Biometric Recognition Group – ATVS  
Escuela Politécnica Superior  
Universidad Autónoma de Madrid, Spain

Pattern Recognition and Image Proc. Lab.  
Dept. of Computer Science & Engineering  
Michigan State University



August, 2008 - PRIP Seminar - Dept. Computer Science and Engineering, Michigan State University